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Audio Analyzer UPD

Tomorrow's digital world today

- For all interfaces: analog, digital and combined
- Programmable digital
 interfaces
- Real dual-channel measurements
- Maximum dynamic range
- Wide bandwidth
- FFT analysis
- Jitter analysis
- Interface tester
- Freely programmable filters
- Versatile functions
- Compact unit with integrated PC
- Automatic test sequences
- Extensive online help



Audio analysis today and tomorrow

Analog and digital

Audio signal processing is nowadays no longer conceivable without the use of digital techniques. Yet, analog technology continues to exist and undergoes constant improvement. State-ofthe-art measuring instruments must therefore be able to handle both analog and digital signal processing.

Audio Analyzer UPD performs practically all types of audio measurement, from frequency response measurements through to externally controlled sweeps with reference traces, determination of 3rd-order difference frequency distortion, spectral display of demodulated wow and flutter signals, etc. In contrast to many other audio analyzers, UPD is capable of performing real dual-channel measurements in the audio-frequency range, ie there is no need for switchover between two inputs and this type of measurement is not limited to a few special cases.

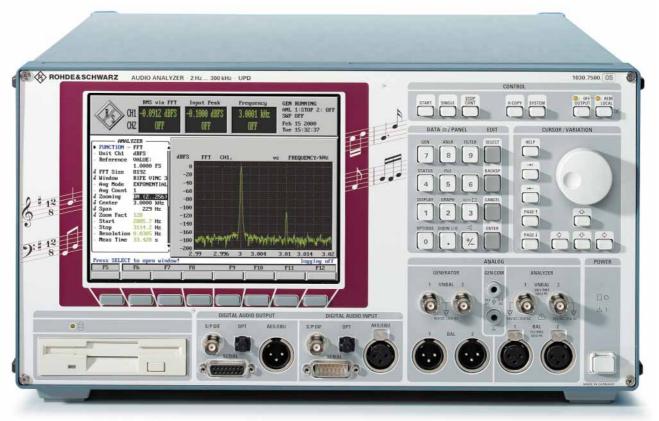
The generator is every bit as versatile: it supplies any conceivable signal from sinewave and noise signals through to multi-sinewave signals comprising up to 7400 frequencies.

In addition to all this, UPD features excellent technical data: analog sinewave generation with harmonics of typ. -120 dB, spectrum displays with a noise floor below -140 dB for analog and -160 dB for digital interfaces, FFT with a maximum frequency resolution of 0.02 Hz, etc.

UPD provides signal monitoring via loudspeaker, jitter measurements on digital audio signals, resynchronization of jittered digital audio signals by means of a jitter-free clock signal, and many more features.

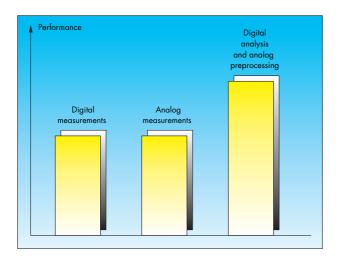
Superior analysis concept

UPD performs all measurements using digital signal processing. Analog signals to be tested undergo elaborate preprocessing before they are digitized and measured by means of digital routines. For example, in THD measurements, the fundamental is attenuated by means of a notch filter and the residual signal amplified by 30 dB before it is digitized. In this way, the dynamic range can be extended beyond that offered by the internal converter. This provides sufficient margin for measuring converters of the future, which will be technically more advanced than those of present-day technology (see graph on the right). This concept guarantees performance and flexibility by far superior to instruments providing purely analog or digital measurements.



The above measurement concept offers many other advantages over merely analog concepts:

- The test routines for analog and digital interfaces are identical. This allows, for instance, the direct comparison of IMD measurements made ahead of and after a converter
- In intermodulation measurements, spurious components are measured selectively for all frequencies in accordance with the mathematical formula of the relevant test standards. This procedure avoids the measurement of adjacent components along with the spuria, which is usually inevitable with analog test methods



The intelligent combination of analog and digital measurement techniques paves the way for future applications

- All test functions are available both on the analog and the digital interfaces. This makes it possible to measure at any point of a common analog and digital transmission path. Only this ensures efficient and complete testing
- The filters, too, are implemented digitally, resulting in an infinite number of filters as it were, and this also for measurements on analog interfaces. Simply choose the type of filter (eg highpass), cutoff frequency and attenuation: that's all you have to do to loop a new filter into the test path
- Measurement speed is as a rule higher than with analog techniques since digital test routines can adapt their speed to the input frequency. And – last but not least:
- Operation is the same for the analog and the digital interfaces. A feature that should not be underestimated



Certified Environmental System

A future-proof investment

Nobody can accurately predict today what effects future developments in digital technology will have on the audio world and what will be the resulting test requirements. This is however no problem for Audio Analyzer UPD. Since all test functions are implemented digitally, UPD can be adapted to changing requirements by simply loading the necessary software – and this also for the analog interfaces.

And one more thing: Rohde & Schwarz is the only manufacturer to equip its audio analyzers with 32-bit floatingpoint signal processors throughout, thus offering plenty of reserves beyond the limits of today's common 24-bit technology.

A competent partner

The name of Rohde & Schwarz stands for excellent quality – thousands of audio analyzers have proven records at satisfied customers and have been in operation successfully for many years.

As a competent partner we shall be pleased to advise you on the optimum use of our instruments. Our representatives are available for you all over the world, and our customer support center and application engineers in Munich help you find the right solution to your measurement tasks. In addition, you will find a wealth of proposals and solutions in our application notes and software.

Naturally, Rohde & Schwarz instruments are certified in compliance with ISO 9001 and ISO 14001.

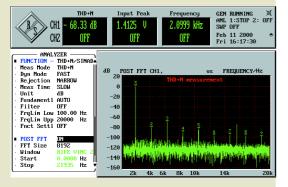


Fig. 1: Automatic marking of harmonics in THD+N measurements makes nonharmonics visible at a glance

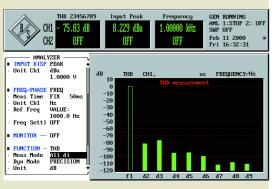


Fig. 2: In THD measurements, single harmonics, all harmonics or any combination of harmonics can be measured

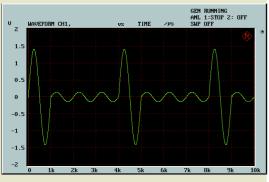


Fig. 3: The waveform function displays the test signal in the time domain. The example shows a sinewave burst

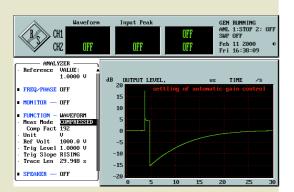


Fig. 4: The transient characteristics of an AGC play an important role in testing hearing aids or automatic volume control on tape recorders

Test signals – as you like it

The generators of UPD supply an extremely wide variety of analog and digital test signals:

• Sinewaves

for level and harmonic distortion measurements. The signal can be applied to an equalizer with userselectable nominal frequency response, eg for compensating the frequency response of the test assembly

Two-tone signal

for modulation distortion analysis. Various amplitude ratios can be selected and the frequencies are continuously adjustable

- Difference tone signal for intermodulation measurements with continuous setting of both frequencies
- Multitone signal comprising up to 17 sinewaves of any frequency and with the same

or different amplitude; setting the phase is also possible • Sine burst signal

- with adjustable interval and ontime as well as programmable low level, eg for testing AGCs
- Sine² burst

also with adjustable interval and on-time, eg for testing rms rectifier circuits

• Special multitone signal comprising up to 7400 frequencies with selectable amplitude distribution. The frequency spacing can be linked to the resolution used for the fast Fourier transform, thus enabling rapid and precise singleshot measurements of the frequency response of a DUT

An allrounder

• Squarewave

as an ideal signal for measuring the transient response of a DUT

- Signal for dynamic intermodulation measurement (DIM) consisting of a squarewave and a sinewave signal with a level ratio of 4:1
- Noise

with a variety of amplitude probability distributions, eg for acoustic measurements; crest factor can be set

- Arbitrary waveforms for generating any voltage curve of up to 16k points
- AM and FM for sinewave signals

• DC also with sweep function

Signals can be generated with an offset. Moreover, digital audio signals can be dithered with adjustable level and selectable amplitude distribution.

Versatile measurement functions

UPD offers a wealth of measurement functions both for analog and digital interfaces.

• Level or S/N

with rms, peak or quasi-peak weighting; high measurement speeds due to automatic adaptation of integration times to input signal

• Selective level

The center frequency of the bandpass filter can be swept or coupled to the generator frequency, to the frequencies of a multitone signal (eg for fast frequency response measurements) or to the input signal



- SINAD or THD+N The sum of all harmonics and noise is measured (Fig. 1)
 Total harmonic distortion (THD)
- Individual harmonics, all the harmonics or any combination of harmonics can be measured (Fig. 2)
- Modulation distortion to DIN-IEC 268-3; 2nd and 3rd order intermodulation is measured
- Intermodulation
 using the difference tone method.
 2nd and 3rd order intermodulation
 is measured

- Dynamic intermodulation measurement on the products specified by DIN-IEC
- Wow and flutter to DIN-IEC, NAB, JIS or the 2-sigma method to DIN-IEC where the demodulated-signal spectrum is also displayed
- DC voltage
- Frequency, phase and group delay
- **Polarity** signal paths are checked for reversed polarity

- Crosstalk
- Waveform function

for representing the test signal in the time domain (Fig. 3). Waveforms can be smoothed by interpolation. Slow sequences can be displayed compressed, eg for analyzing the transient response of compander or AGC circuits (Fig. 4)

• Coherence and transfer functions for determining the transfer characteristics of complex test signals



Tests on hi-fi components call for increasingly complex measurement techniques. Results obtained in the test lab must be verified in production, where as a rule not the whole range of test functions is needed. Audio Analyzer UPD and its "little brother" UPL complement each other. The operating concept of the two units based on the same IEC/IEEE-bus commands is identical, so there is no problem using them jointly

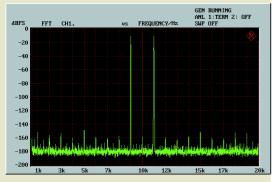


Fig. 5: FFT spectrum of two-tone signal shown on full screen

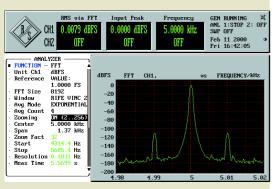


Fig. 6: With the zoom FFT function, sidebands spaced only a few hertz from the signal can be displayed

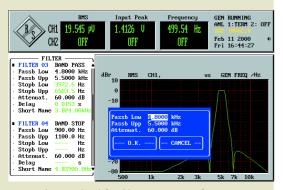


Fig. 7: Filters can be defined by entering just a few parameters

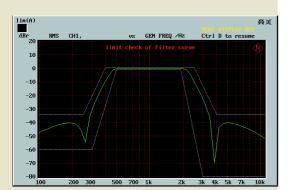


Fig. 8: Tolerance curves enable fast go/nogo tests

Spectrum analysis

With its FFT analyzer, UPD is also capable of spectrum analysis. The number of samples for fast Fourier transform can be selected between 256 and 16k in binary steps (Fig. 5). A special feature is zoom FFT. The signal to be measured is digitally preprocessed to increase the frequency resolution by a factor of 2 to 256 over a selectable range. In this way, a maximum resolution of 0.02 Hz is attained. It should be emphasized that this is not just a scale expansion but the measurement is really made at a higher resolution (Fig. 6).

Programmable filters

The filters of UPD are software-implemented so that the user can define any number of filters. The most common weighting filters are provided as standard. Further filters can be programmed in a few seconds by entering the type (lowpass, highpass, bandpass, bandstop, notch, third octave or octave), frequency and attenuation (Fig. 7). The instrument's open architecture shows its strength in particular where special requirements have to be met: special filters can be implemented using commercial filter design programs. The data are transferred to UPD and the created filter is looped into the signal path.

A variety of sweep functions

For continuous variation of the test signals, UPD offers amplitude and frequency sweeps and for bursts additionally sweeps of interval and on-time. Sweeps are defined either by means of a table or via parameters such as start value, number of steps, linear/log stepping or time interval. It is also possible to sweep two variables simultaneously.

In measurements of external signals, these can be used for analyzer sweeps (external sweeps). Many different start conditions can be set, allowing measurements to be triggered by a variety of events. Results will be stable even for DUTs with unknown or unstable transient response thanks to the settling function.

All-in package

Audio Analyzer UPD is a compact unit with an integrated controller. It avoids the disadvantages of external PC control, which is found in other audio analyzers.

The instrument is easy to transport as it requires no external equipment such as keyboard, monitor or other PC peripherals.

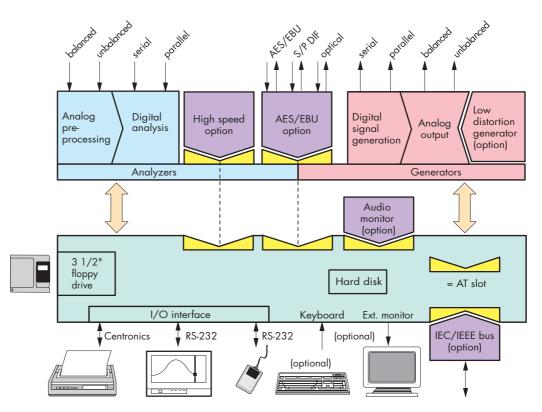
UPD is supplied ready for use. Installation is nothing more than unpacking the unit and switching it on for starting the measurement. The user is not burdened with problems that cropped up in the past with the installation of interface cards or PC software.

With audio analyzers controlled from an external PC, interference may be radiated from the PC, monitor or interface connections, which distorts measurement results. Not so with UPD: the instrument has specified EMC characteristics which also include the internal PC. In contrast to conventional PCs, UPD features elaborate screening such as magnetically shielded power transformers and coated filter pane in front of the display.

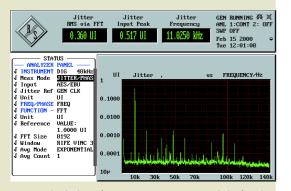
And a real boon: the price of UPD includes the internal PC.

- Built-in hard disk and disk drive
- Connectors for keyboard, mouse, monitor, printer and plotter
- Centronics interface for connecting
 printer or network
- Drivers for commercial printers are supplied as standard
- Remote control via IEC/IEEE bus

- Postprocessing of results directly in UPD using standard software
- All results available in the common data formats, making it easy to import graphics into documents, for example
- Easy loading of function and software extensions via floppy disk
- Automatic test sequences and measurement programs with universal sequence controller. Easy generation of programs with built-in program generator



Block diagram of UPD





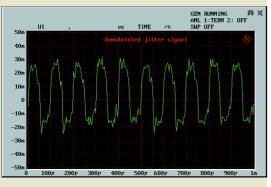


Fig. 10: Display of jitter signal in time domain



Fig. 11: Complete measured-value tables can be output for all functions

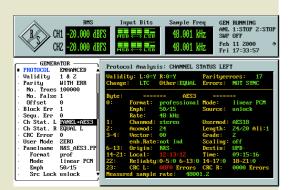


Fig. 12: UPD generates and analyzes additional data in digital data streams in line with all common standards. The data are represented in binary form, as hexadecimal numbers, as ASCII characters or evaluated in consumer or professional format

Interfaces, protocol analysis, jitter

Analog interfaces

- Balanced inputs and outputs with high common-mode rejection and various impedances commonly used in the studio. Measurements can be made on lines with phantom feed
- Unbalanced inputs and outputs, floating (eg to prevent hum loops)
- The generator outputs can be internally connected to the analyzer inputs so that different types of measurement can be made without the need for changing the cabling

Programmable digital audio interfaces

- Parallel inputs and outputs for connecting modules or converters with parallel interface
- Serial inputs and outputs for adapting modules with a non-standard serial interface or audio chips. This interface is user-programmable, ie by selecting the word length, clock polarity, position of sync pulse, etc, it can be matched to almost any serial format, eg also to l²S bus
- Word lengths up to 32 bits with max. 28 audio bits open up a wide application range. Clock rates up to 1 MHz (word clock) can be processed

Standardized digital audio interfaces (option UPD-B2)

- Balanced (XLR), unbalanced (BNC) and optical (TOSLINK) inputs and outputs for connecting consumer electronics and professional studio equipment
- The levels of the balanced and unbalanced outputs are adjustable so that the sensitivity of digital audio inputs can be determined

- The format of the generated channel status data may be professional or consumer irrespective of the selected interface
- The clock rates of the analyzer and generator are independent of each other. This allows measurements on sample rate converters
- The word length can be selected between 8 and 24 bits independently for generator and analyzer



 Analysis of channel status and user data. The data are output in binary form, as hexadecimal numbers, as ASCII characters or, in the case of channel status data, evaluated in the professional or consumer format to AES 3 or IEC 958 (Fig. 12)

- Generation of channel status data, user data and validity bits. Channel status data can be entered in binary form or via panel to AES 3 or IEC 958 in the professional or consumer format
- Any bits can be combined under a symbolic name. In this way, data input and representation can easily be adapted to customer requirements
- Simultaneous measurement of clock rate and display of interface errors (such as parity error)
- Generation of parity and CRC errors, etc, for testing input circuits
- An additional high-impedance input permits measurements to be performed without opening the signal path

Jitter and interface tests (option UPD-B22)

With this option, the physical parameters of digital audio interfaces can be examined. UPD-B22 extends the functions of option UPD-B2

Signal analysis:

- Measurement of jitter amplitude and display of jitter signal in the frequency and time domain (Figs 9 and 10)
- UPD generates bit- or word-synchronous sync signals that allow the accurate display of digital audio signals on an oscilloscope (preamble, eye pattern, signal symmetry, superimposed noise, etc)
- Measurement of input pulse amplitude and sampling frequency
- Measurement of phase difference between audio and reference input signal
- Analysis of common-mode signal of balanced input (frequency, amplitude, spectrum, etc.)

Digital components of various data formats and clock rates are the stock-in-trade of professional users. They call for a measuring instrument offering top performance at all interfaces at high accuracy and over a wide dynamic range. Operation is identical for analog and digital interfaces, which enhances operator convenience. Fast fault diagnosis is possible by means of stored test routines, allowing the elimination of problems immediately before transmission



Signal generation:

- The clock of the output signal can be "jittered" by superimposing a sinewave or noise signal of variable amplitude
- An input signal with jitter can be output jitter-free
- A common-mode signal can be superimposed on the balanced output signal
- Long cables can be simulated by means of a switchable cable simulator
- The phase shift between the digital audio output and the reference output can be varied
- A reference (XLR) input and a synchronization (BNC) input provided on the rear panel allow the generator to be synchronized to the digital audio reference signal to AES 11, word clock, video sync signals (PAL, SECAM, NTSC) and to 1024 kHz reference clocks
- Generation of variable clock signals from 30 kHz to 52.5 kHz, also for operating UPD-B2
- Adjustable pulse amplitude

Designed for convenience

Efficient online help

UPD offers a variety of help functions to provide optimum support for the user:

HELP function

HELP information in German or English can be called for each input field.

SHOW I/O key

If no results can be displayed, eg because no input signal or an incorrect input signal is present, information on possible causes will appear upon pressing SHOW I/O. Moreover, the input and output configuration will be displayed.

Info boxes

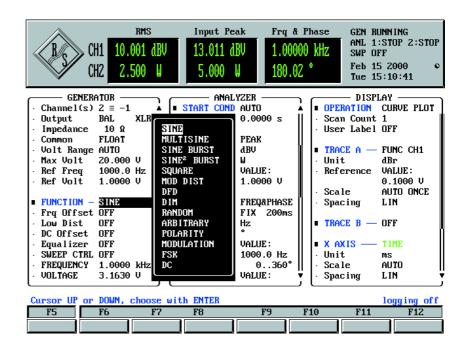
These highlighted boxes inform the user of any incorrect settings.

Online help

The permissible range of values is indicated for each menu item requiring the entry of a numerical value. This range takes into account any limitations resulting from related parameters, eg the sample rate in the case of measurements on digital interfaces.

Protection against illegal entries

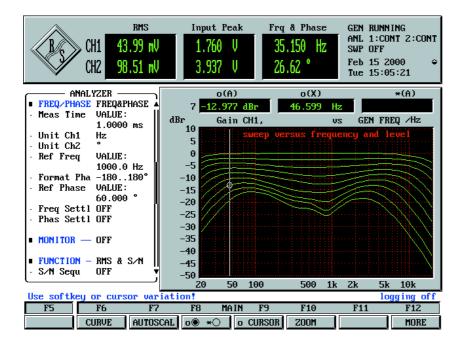
UPD will not accept entries outside the permissible range. An alarm tone will be issued and the value changed to the permissible minimum or maximum value.

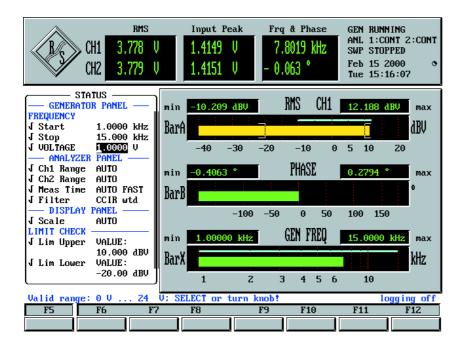


A wealth of functions – yet easy to operate

- Related functions and settings are combined in panels that can be called at a keystroke. Up to three panels can be displayed at a time
- The operator is not burdened with unnecessary information. Only the parameters and settings needed for a given application are displayed – the others are available in the background. For example, the sweep parameters are transferred to the generator panel and displayed only when the sweep function is activated
- Fast access to frequently used instrument setups and a comprehensive library of standard measurements simplify familiarization with the instrument

- Uncomplicated entries: the user simply needs to open a menu and make an entry or selection
- Continuous status information on generator, analyzer and sweep
- Rapid operating sequences through the use of softkeys, eg for graphical representations
- The user can choose between operation via mouse, external keyboard or front panel. This choice makes sense since the working space required by a mouse is not always available
- Short learning time thanks to an easy-to-understand operating concept treating analog and digital measurements in the same way





Results at a glance

- Real-time display of results for one or both channels and several test functions
- Simultaneous display of frequency and phase
- With graphics, results can be read off with vertical and horizontal cursors. Tolerance curves or stored results can be added for comparison
- Sets of traces can be displayed, stored and evaluated for both channels
- Graphics modes range from traces and bargraphs through spectrum display to three-dimensional waterfalls

It is often the case that only a few parameters need to be modified after a measurement sequence has been started. Therefore, entry lines can be selected from the input panels for the generator, analyzer, etc, by marking them with a tick. They are then transferred to a status panel. The status panel thus gives a summary of parameters for a measurement routine, which offers the following advantages:

- Instrument settings can be displayed together with graphical and numerical results
- All important information can be printed on a single hardcopy
- Instrument settings can be modified quickly without changing panels as UPD can also be operated from the status panel

Fast and efficient

High measurement speed

In designing Audio Analyzer UPD, particular emphasis was placed on optimizing the measurement speed of the test system as a whole:

- All operations involving elaborate computing are carried out by digital signal processors. The PC is merely used for control of the unit and display of results
- UPD can perform even complex test functions simultaneously on both channels with the built-in highspeed option UPD-B3. This feature alone reduces the time for stereo measurements by 50% compared with most analyzers available on the market
- The digital test routine adapts its speed optimally to the input frequency. This enhances measurement speed especially in the case of frequency sweeps
- UPD performs harmonic distortion and IMD measurements using patented, digital test procedures that combine high accuracy with high measurement speed
- Digital signal processing reduces setting and transient times achievable with purely analog instruments. These times are also taken into account in the test routines, yielding stable measurements without the need for activating settling functions (these are understood to be repeated measurements until results are within a tolerance band)
- User interface tailored to the requirements of a test, not of an office environment
- Display windows not needed can be switched off, which also cuts down the processing time

Use in production

Instruments to be used in production tests must satisfy a variety of requirements:

- High measurement speed is vital for achieving a high production throughput. By making appropriate use of the instrument functions, go/nogo decisions can be made already in the audio analyzer, thus reducing the run time of a DUT (Fig. 8)
- Two-channel measurements allow the simultaneous and thus timesaving determination of input and output characteristics

- The use of FFT analysis provides a decisive advantage especially in the case of frequency response measurements, which are particularly time-critical
- Long calibration intervals, resulting from the extensive use of digital circuits, make for high availability of the instrument
- Remote-control capability via the IEC/IEEE bus is a must in large-scale production systems. In the design of Audio Analyzer UPD, special importance was attached to data transfer via the IEC/IEEE bus. The logging mode can be used to speed up the generation of control programs for the IEC/IEEE bus. With the program generator provided in UPD-K1, it is no longer necessary to look up IEC/ IEEE-bus commands

Options for further applications

Low distortion generator

The low distortion generator is essential for all applications requiring extremely pure analog signals or generation of an analog DIM signal. Its inherent distortion is well below that of the built-in universal generator which already has excellent specifications.

AES/EBU interface

This interface option (UPD-B2) contains the AES/EBU, the S/P DIF and the optical interfaces. An additional signal processor on the PCB permits also user bits, status bits, parity and CRC errors, etc, to be generated and analyzed in addition to audio data. Input and display masks can be userdefined with the aid of configuration files for adapting the interface to any protocol. Ready-made masks are available for protocols to AES3 or consumer format. The output level of the interface can be programmed. An additional high-impedance input enables measurements without opening the signal path.

Option UPD-B22 permits also the physical parameters of the serial bit stream of the digital audio interface to be investigated (for details refer to page 9).

High-speed option

UPD was designed for high measurement speed. For this reason all analog switching circuits are provided with two channels. Operations for the two measurement channels are calculated in time multiplex. If higher measurement speed is needed – eg in production – the optional High speed Extension UPD-B3 can be used. With the aid of this option digital processing too is performed in parallel for the two channels.

Audio monitor

The optional Audio Monitor UPD-B5 adds a headphones output and a builtin loudspeaker to UPD. During rms measurements in the frequency range up to 20 kHz, the input signal and the filtered signal can be monitored at the interfaces of the analog analyzer and the AES/EBU option.

UPD-B5 is also provided with four TTL inputs and eight TTL outputs which can be used for instance for switching checkpoint selectors.

IEC/IEEE-bus option

IEC-625/IEEE-488 bus Interface UPD-B4 enables remote control of UPD to IEC 625/IEEE 488. The employed commands largely meet SCPI standards.



Universal sequence controller

This option (UPD-K1) allows measurement sequences to be generated and executed, thus turning UPD into an automatic test system. Programming of measurement sequences is greatly facilitated by the built-in program generator:

Each manual control step is recorded in the logging mode and translated into a complete line of the sequence program with correct syntax, ie test sequences can be programmed without a single line to be typed by the user. The program thus generated does not just give the sequence of keys to be pressed but contains the instructions in easy-to-read IEC/IEEE-bus syntax according to SCPI. BASIC commands can then be used to modify the program, eg for branching or graphic outputs.

Complete application programs based on the universal sequence controller are available to the user for measurements on CD players, tuners, etc.

With the IEC/IEEE-bus option

(UPD-B4) fitted, the universal sequence controller can also be used for remote control of external IEC/IEEE-bus equipment. Moreover, programs generated on UPD can be transferred after slight modifications to an external controller for the remote control of UPD. This greatly facilitates the generation of remote-control programs.

Automatic line measurement

Option UPD-K33 serves for automatic measurements of all relevant parameters of broadcast links according to ITU-T O.33. Generator and analyzer are normally located at different sites. They are synchronized with the aid of FSK signals. The operator may utilize the standard sequences defined by ITU-T O.33 or prepare his own.

Option UPD-K1 is needed for the use of UPD-K33.

Specifications

Data without tolerances are typical values

Analog analyzers

Three analyzers differing in bandwidth, specifications and measurement functions are available for analog measurements.

Analyzer ANLG 22 kHz ANLG 100 kHz ANLG 300 kHz Voltage measurement ranges

Measurement accuracy Frequency response¹⁾ 20 Hz to 22 kHz 10 Hz to 20Hz 22 kHz to 50 kHz 50 kHz to 100 kHz 100 kHz to 300 kHz

Inputs

Balanced

Voltage range Input impedance

Crosstalk attenuation Common mode rejection (V_{in} <3 V)

Common mode voltage (V_P)

Unbalanced

Voltage range Input impedance Crosstalk attenuation Common mode rejection (V_{in}<3 V)

Common mode voltage (V_P)

Generator output

Measurement functions

RMS value, wideband Measurement accuracy Measurement speed AUTO AUTO FAST Frequency range 2 Hz/10 Hz to 21.90 kHz 20 Hz to 100 kHz 50 Hz to 300 kHz 5 dB steps for V_{in} >300 mV, 10 dB steps for V_{in} <300 mV ±0.05 dB at 1 kHz (sine, rms)

 $\pm 0.03 \text{ dB}$ $\pm 0.15 \text{ dB}$ $\pm 0.1 \text{ dB}$ $\pm 0.2 \text{ dB}$ $\pm 1.0 \text{ dB}$

- 2 independent channels XLR connectors (female), floating 0.1 μ V to 35 V (rms, sine) 300 Ω , 600 Ω , 20 k Ω ±0.5% each, one value <20 k Ω specified by user (ready for installation), parallel 200 pF >120 dB, frequency <22 kHz >110 dB at 50 Hz, >86 dB at 1 kHz, >60 dB at 16 kHz max. 50 V (safety regulation), protected by surge protector
- 2 independent channels BNC connectors (female), floating/ grounded switchable 0.1 μV to 300 V (rms, sine) 1 MΩ||200pF >120 dB, frequency <22 kHz >110 dB at 50 Hz, >86 dB at 1 kHz, >60 dB at 16 kHz max. 50 V (safety regulation), protected by surge protector

each input switchable to any output, input impedance: balanced 200 k $\Omega,$ unbalanced 100 k Ω

±0.05 dB at 1 kHz, sine ±0.1 dB additional error Integration time AUTO FAST AUTO VALUE Noise (600 Ω) with A weighting filter with CCIR unweighting filter Filter

Spectrum

RMS value, selective Bandwidth (–0.1 dB)

Selectivity

Frequency setting

Measurement accuracy

Peak value Measurement

Measurement accuracy Interval Filters

Quasi-peak Measurement, accuracy Noise (600 Ω) Filter

DC voltage

Voltage range

Measurement accuracy Measurement range

S/N measurement routine

FFT analysis

Total harmonic distortion (THD) Fundamental Frequency tuning

Weighted harmonics

Measurement accuracy,		
harmonics	<50 kHz	
	<100 kHz	
	<300 kHz	

4.2 ms, at least 1 cycle 42 ms, at least 1 cycle 1 ms to 10 s

1 μV <2 μV (typ. 1.6 μV) weighting and user-definable filters, up to 4 filters combinable additional analog notch filter (dynamic range expanded by up to 30 dB) post-FFT of filtered signal

1%, 3%, 1/12 octave, 1/3 octave and user-selectable fixed bandwidth, minimum bandwidth 20 Hz 100 dB, bandpass or bandstop filter, 8th order filter, elliptical

- automatic to input signal
 coupled to generator
- fixed through entered value

sweep in user-selectable range
 ±0.2 dB + ripple of filters

with analyzer ANLG 22 kHz only peak max, peak min, peak-to-peak, peak absolute ±0.2 dB at 1 kHz 20 ms to 10 s weighting filters and user-definable filters, up to 3 filters combinable

with analyzer ANLG 22 kHz only to CCIR 468-4 <8 μV with CCIR weighting filter weighting and user-definable filters, up to 3 filters combinable, analog notch filter in addition

0 to ±300 V unbalanced 0 to ±35 V balanced ±(1.5% + 2 mV) 100 mV to 300 V (balanced 30 V), 10 dB steps

available for measurement functions – rms, wideband – peak – quasi-peak

indication of S/N ratio in dB, no post-FFT

see FFT analyzer section

6 Hz to 110 kHz

±0.5 dB ±0.7 dB ±1.5 dB

- automatic to input signal
- coupled to generator
 fixed through entered value any combination of d₂ to d₉, up to max. 300 kHz

¹⁾ Relative to 1 kHz, sine, rms. Additional error ±0.1 dB for voltages >60 V unbalanced (>10 V balanced) and frequencies >50 kHz. For analyzer ANLG 22 kHz with lower measurement limit 2 Hz (min. freq. 2 Hz): ±0.03 dB from 10 Hz to 22 kHz, ±0.05 dB from 2 Hz to 10 Hz. Inherent distortion¹⁾ Analyzer ANLG 22 kHz <-110 dB, typ. -115 dB Fundamental >100 Hz 20 Hz to 100 Hz $< -100 \, dB$ 10 Hz to 20 Hz <-96 dB Analyzer ANLG 100 kHz 50 Hz to 20 kHz <-97 dB, typ. -105 dB Fundamental $20\ensuremath{\,\text{kHz}}$ to $50\ensuremath{\,\text{kHz}}$ <-92 dB Analyzer ANLG 300 kHz 130 Hz to 20 kHz Fundamental <-97 dB, typ. -105 dB 20 kHz to 50 kHz <-92 dB 50 kHz to 110 kHz <-86 dB Spectrum bar chart showing signal and distortion

20 Hz to 110 kHz

+0.5 dB

±0.7 dB

±1.5 dB

automatic to input signal

fixed through entered value

 $>100 \,\mu\text{V}$ typ. with automatic tuning

upper and lower frequency limit se-

lectable, one additional weighting filter

- coupled to generator

THD+N and SINAD

Fundamental Frequency tuning

Input voltage Bandwidth

Measurement accuracy Bandwidth <50 kHz <100 kHz <300 kHz

Inherent distortion²⁾ Analyzer ANLG 22 kHz Bandwidth 20 Hz to 21.90 kHz typ. -110 dB at 1 kHz, 2.5 V <-105 dB +2 μV typ. –108 dB +1.5 μ V ³⁾ Analyzer ANLG 100 kHz Bandwidth 142 Hz to 22 kHz <-95 dB + 2.5 µV, typ. -100 dB + 1.75 µV 142 Hz to 100 kHz <-88 dB + 5 μV, typ. -95 dB + 3.5 μV Analyzer ANLG 300 kHz Bandwidth 427 Hz to 22 kHz <-97 dB + 2.5 μV, typ. -100 dB + 1.75 μV $\begin{array}{l} 427 \text{ Hz to } 100 \text{ kHz } < -90 \text{ dB} + 5 \ \mu\text{V}, \text{ typ.} - 95 \text{ dB} + 3.5 \ \mu\text{V} \\ 427 \text{ Hz to } 300 \text{ kHz } < -85 \text{ dB} + 10 \ \mu\text{V}, \text{ typ.} - 92 \text{ dB} + 7 \ \mu\text{V} \end{array}$

Modulation factor (MOD DIST)

Measurement method selective to DIN-IEC 268-3 30 to 1200 Hz Frequency range lower frequency 8xLF to 100 kHz⁴⁾ upper frequency Measurement accuracy +0.50 dB 4 to 15 kHz 15 to 20 kHz <-96 dB (-85 dB)

post-FFT of filtered signal

Spectrum

Inherent distortion⁵

Upper frequency

Spectrum

<-96 dB (-90 dB), typ. -103 dB bar chart showing signal and distortion

Difference frequency distortion (DFD)

Measurement method Frequency range difference frequency 80 Hz to 1 kHz center frequency Measurement accuracy Inherent distortion⁷ DFD d₂ DFD d₃ Spectrum

Dynamic intermodulation distortion (DIM)

Measurement method

Test signal

Measurement accuracy Inherent distortion⁸⁾ Spectrum

Wow and flutter Measurement method

OFF Weighting filter ON Measurement accuracy Inherent noise

Spectrum

Time domain display (WAVEFORM)

Triaae Trigger level Standard mode Trace length Interpolation

Enhanced mode Trace length Compressed mode

Coherence and transfer function

Frequency range Frequency resolution Averaging FFT length

Frequency

Frequency range Accuracy Input voltage

selective to DIN-IEC 268-3 or 118 200 Hz to 100 $\rm kHz^{6)}$ ± 0.50 dB, center frequency <20 kHz <-115 dB, typ. -125 dB <-96 dB, typ. -105 dB bar chart showing signal and distortion

with analyzer ANLG 22 kHz only selective weighting of all 9 interference lines to DIN-IEC 268-3 square/sine 3.15 kHz/15 kHz or 2.96 kHz/14 kHz, frequency tolerance ±3% any square/sine amplitude ratio (standard 4:1) ±1 dB <-80 dB, typ. -90 dB bar chart showing signal and distortion

with analyzer ANLG 22 kHz only DIN-IEC, NAB, JIS, 2-sigma to IEC-386 highpass 0.5 Hz, bandwidth 600 Hz bandpass 4 Hz to IEC-386 ±3% <0.0005% weighted <0.001% unweighted post-FFT of demodulated signal

rising/falling edge -300 V to +300 V, interpolated between samples

max. 7424 points 1, 2, 4, 8, 16, 32 single channel max. 65530 points 2- to 1024-fold compression (envelope for AGC measurement), with analyzer ANLG 22 kHz only

with analyzer ANLG 22 kHz only DC to 21.9 kHz from 5.86 Hz 2 to 2048 256, 512, 1 k, 2 k, 4 k, 8 k points

2 Hz to 300 kHz ±50 ppm >5mV

- ¹⁾ Total inherent distortion of analyzer and generator (with option UPD-B1), analyzer with dynamic mode precision >10 V: typ. 3 dB lower; <0.5 V: sensitivity reduced by inherent noise
- (typ. 0.25/1.25/2.5 μV with analyzers ANLG 22/100/300 kHz). ²⁾ Total inherent distortion of analyzer and generator (with option UPD-B1), analyzer
- with dynamic mode precision, fundamental <100 kHz
- At full-scale measurement range (<-100 dB + 2 μ V with auto range). $<-100 \text{ dB} + 2 \mu \text{V}$ for fundamental < 100 Hz. <–100 dB for input voltage >5 V.
- 4) For upper frequency >20 kHz the bottom limit of the lower frequency is reduced.
- Input voltage >200 mV, typical values apply between 0.5 and 5 V. Lower frequency >200 Hz, values in () for lower frequency <200 Hz. Dynamic mode precision; level ratio LF:UF = 4:1.
- 6) For center frequency >20 kHz the bottom limit of the difference frequency is reduced. 7)
- Input voltage >200 mV, typical values apply between 0.5 V and 5 V, dynamic mode precision (at DFD d_2), center frequeny 5 kHz to 20 kHz.
- Input voltage >200 mV, typical values apply between 0.5 V and 5 V. Total inherent distortion of analyzer and generator at full-scale measurement range.

Phase

Accuracy at 1 kHz 20 Hz to 25 $kHz^{1)}$ 10 Hz to 20 Hz 25 kHz to 100 kHz Input voltage

Display range

Group delay

Frequency range Accuracy in seconds

Polarity test

Measurement Display

Analog generators

A 20-bit D/A converter is used for analog signal generation. Two generators differing in frequency ranges, specifications and test signals are available: Generator Frequency range Sample Rate ANLG 25 kHz 2 Hz to 25 kHz 96 kHz ANLG110 kHz 2 Hz to 110 kHz 384 kHz The characteristics of the basic generator can be improved and extended with a low-distortion RC oscillator (Low Distortion Generator UPD-B1): -sine with reduced distortion

±0.1° typ.

±0.4°

±1.0°

±1.75°

cal level

 $\pm 180^\circ$ or 0 to 360°

20 Hz to 100 kHz

where $\Delta \phi$ = phase accuracy in °, Δf = frequency step

polarity of unsymmetrical input signal

 $\Delta \phi / (\Delta f \times 360),$

+POL, -POL

> 15 mV, both signals of almost identi-

-improved intermodulation signals DFD and MODDIST

-signal generation for dynamic intermodulation measurement DIM

Outputs

Balanced	XLR connectors (male), 2 channels, floating/grounded switchable, short-circuit-proof; external feed <120 mA 0.1 mV to 24 V (rms, sine, open-circuit)	20 Hz to 2 kHz 2 kHz to 7 kHz 7 kHz to 20 kHz 20 kHz to 50 kH 50 kHz to 100 k	lz <-92 dB
Voltage Crosstalk attenuation Source impedance	>117 dB, frequency <20 kHz 10 Ω 30 $\Omega \pm 0.5\Omega$, 200 Ω , 600 Ω , $\pm 0.5\%$ in each case, one user-selectable value >30 Ω , ready for installation	Fundamental 1 kHz, 2.5 V 100 Hz to 20 kl 20 Hz to 100 H <100 kHz <20 kHz <100 kHz	
Load impedance	>400 Ω (incl. source impedance)	Sweep parameters	frequency
Output balance	>80 dB at 1 kHz,		
(output floating)	>60 dB at 20 kHz	MOD DIST	for measu
Unbalanced	BNC connectors (female), 2 channels, floating/grounded switchable, short-circuit-proof; external feed <120 mA	Frequency range lower frequen upper frequen Level ratio (LF:UF)	,
Voltage	0.1 mV to 12 V (rms, sine, open-circuit)	Level accuracy	±0.5 dB
Crosstalk attenuation Source impedance	>117 dB, frequency <20 kHz 5 Ω 15 Ω±0.5Ω,	Inherent distortion	<–80 dB (t upper frea level ratio
	one user-selectable value > 15Ω , ready for installation	Sweep parameters	upper free
Load impedance	>200 Ω	MOD DIST (with low distortion ge	nerator option)
		Frequency range lower frequen upper frequen	
		Level ratio (LF:UF)	selectable
		Level accuracy	±0.5 dB

Signals

Signals			
Sine			
Frequency range	9		
Generator AN	NLG 25 kHz	2 Hz to 25 kHz	
Generator AN	NLG 110 kHz	2 Hz to 110 kHz	
Frequency accu	racy	±50 ppm	
Level accuracy	anaa (raf ta 1 kHz)	±0.1 dB at 1 kHz	
20 Hz to 20 k	onse (ref. to1 kHz) Hz	±0.05 dB	
2 Hz to 110 k		±0.1 dB	
Inherent distortion	on THD+N LG 25 kHz, fundamen	tal 20 Ha ta 25 kHa	
Measurement			
20 Hz to 22 k	Hz	<-92 dB, typ96 d	IB
20 Hz to 100	kHz	<–87 dB	
Generator AN	LG 110 kHz, fundame	ental 20 Hz to 100 kHz	Z
Measurement	bandwidth		
20 Hz to 22 k 20 Hz to 100		<-94 dB, typ98 d <-80 dB	IB
Sweep paramet		frequency, level	
oweep paramet		nequency, lever	
Sine (with low d	istortion generator op	otion)	
Frequency rang	e	2 Hz to 110 kHz	
Frequency accu	racy		
PRECISION		±0.1%	0.00
FAST		±0.5% at 15°C to 3 ±0.75% at 5°C to 4	
Level accuracy		±0.1 dB at 1 kHz	5 6
,	onse (ref. to 1 kHz)	_011 05 01 1 1012	
20 Hz to 20		±0.05 dB	
10 Hz to 110) kHz	±0.1 dB	
Harmonics		typ. <-120 dB (<-13	30 dB at 1 kHz),
		measurement bandy	vidth
		20 Hz to 20 kHz, voltage 1 V to 5 V	
Inherent distortio	on	THD	
Fundamental	1 kHz, 1 V to 10 V		
	20 Hz to 2 kHz 2 kHz to 7 kHz	<-113 dB <-110 dB	
	7 kHz to 20 kHz	<-105 dB	
	20 kHz to 50 kHz	<–92 dB <–86 dB	
	50 kHz to 100 kHz	<-00 db	
		THD+N ²⁾	Meas. bandw.
Fundamental	1 kHz, 2.5 V 100 Hz to 20 kHz	–110 dB typ. <–105 dB +2 μV	22 kHz 22 kHz
	20 Hz to 100 Hz	$<-100 \text{ dB} + 2 \mu \text{V}$ $<-100 \text{ dB} + 2 \mu \text{V}$	22 kHz
	<100 kHz	<-90 dB +5 µV	100 kHz
	<20 kHz <100 kHz	<-88 dB +10 μV <-85 dB +10 μV	300 kHz 300 kHz
Sweep paramet		frequency, level	500 KHZ
MOD DIST		for measuring the mo	odulation distortion
Frequency rang	e lower frequency	30 Hz to 2.5 kHz	
	upper frequency	8xLF to 110 kHz	
	r)	(max. 25 kHz with A	,
Level ratio (LF:U Level accuracy	r)	selectable from 10:1 ±0.5 dB	1 to 1:1
Inherent distortio	20	±0.5 dB <−80 dB (typ. −90 dB	9
		upper frequency 4 k	y Hz to 25 kHz,
		level ratio $LF:UF = 4$:1
Sweep paramet	ers	upper frequency, lev	rel
MOD DIST (with	low distortion genero	ator option)	
	e lower frequency	30 Hz to 500 Hz	
	upper frequency	4 kHz to 110 kHz	
Level ratio (LF:U	F)	selectable from 10:1	l to 1:1
I accel and a second second			

²⁾ Total inherent distortion of analyzer and generator, analyzer using dynamic mode precision. When the low-impedance source resistors are used (unbalanced 5 Ω , balanced 10 Ω), the THD+N value in level range 0.6 V to 2.5 V balanced (0.3 V to 1.25 V unbalanced) is reduced by typ. 3 dB because of noise.

 $^{1)}$ $\pm 0.4^{\circ}$ above 2 Hz, with analyzer ANLG 22 kHz and lower measurement limit 2 Hz (min. freq. 2 Hz).

Inherent distortion¹⁾

Upper frequency 4 kHz to 15 k	Hz <-96 dB (- 90 dB), typ103 dB
15 kHz to 20	kHz <-96 dB (- 85 dB)
Sweep parameters	upper frequency, level

DFD

for measuring the difference tone 80 Hz to 1 kHz Frequency range difference freq. center frequency 200 Hz to 109 kHz (max. 24 kHz with ANLG 25 kHz) ±0.5 dB level accuracy Inherent distortion²⁾ DFD d₂ <-114 dB, typ.-120 dB DFD d₃ < -85 dB, typ. -95 dB Sweep parameters center frequency, level

DFD (with low distortion generator option)

Frequency range Difference frequeny Center frequency Level accuracy Inherent distortion³⁾ DFD d₂ DFD d₃

80 Hz to 1 kHz 200 Hz to 109 kHz ±0.5 dB <-120 dB, typ.-125 dB < -96 dB, typ. -105 dB center frequency, level

DIM (only with option UPD-B1)

Waveform

Max. level (V_{PP}) Level accuracy Inherent distortion⁴⁾ Sweep parameters

Sweep parameters

Multi-sine

Characteristics

Generator ANLG 25 kHz Frequency range Frequency spacing

Dynamic range Generator ANLG 110 kHz Frequency range Frequency spacing

Dynamic range

Squarewave

Frequency range Max. level (V_{PP}) Level accuracy Rise time Sweep parameters

for DIM measurements to DIN-IEC 268-3 (dynamic intermodulation distortion) square/sine 3.15 kHz/15 kHz or 2.96 kHz/14 kHz, square/sine amplitude ratio 4:1. bandwidth (3 dB) 30 kHz/100 kHz, selectable 50 V (25 V unbalanced) ±0.5 dB < -80 dB, typ.-90 dB level

- 1 to 17 spectral lines -level, frequency and phase selectable for each line - crest factor optimized to minimum or selectable

5.86 Hz to 25 kHz adjustable from 5.86 Hz with <0.01% resolution or matching to FFT frequency spacing 100 dB referred to total peak value

23.44 Hz to 110 kHz adjustable from 23.44 Hz with <0.01% resolution or matching to FFT frequency spacina 80 dB referred to total peak value

with generator ANLG 25 kHz only 2 Hz to 10 kHz 40 V (20 V unbalanced) ±0.2 dB (rms) 1.5 µs frequency, level

Sine burst, sine² burst

Burst time Interval Low level

Bandwidth

Sweep parameters

Noise

Noise in time domain Distribution Noise in frequency domain Frequency range Generator ANLG 110 kHz Generator ANLG 110 kHz Frequency spacing

Distribution Crest factor

Arbitrary waveform Memory depth Clock rate

Bandwidth

Polarity test signal Sine² burst with following characteristics: Frequency On-time Interval

FM signal

Carrier frequency Modulation frequency Modulation

AM signal

Carrier frequency Modulation frequency Modulation

DC voltage Level range

Accuracy

DC offset⁵⁾

Accuracy Residual offset

1 sample up to 60 s, 1-sample resolution burst time up to 60 s, 1-sample res. 0 to burst level, absolute or relative to burst level (0 with sine² burst) 25 kHz/110 kHz with generator ANLG 25 kHz/110 kHz (elliptical filter) burst frequency, level, time, interval

Gaussian, triangular, rectangular

5.86 Hz to 25 kHz 23.44 Hz to 110 kHz adjustable from 5.86 Hz (above 23.44 Hz with ANLG 110 kHz) with <0.01% resolution or matching to FFT frequency spacing white, pink, 1/3 octave, defined by file optimized to minimum or selectable

loaded from file max. 16384 96 kHz/384 kHz with generator ANLG 25 kHz/110 kHz 25 kHz/110 kHz with generator ANLG 25 kHz/110 kHz (elliptical filter)

with generator ANLG 25 kHz only

12 kHz 1 cycle (0.8333 ms) 2 cycles (1.6667 ms)

with generator ANLG 25 kHz only 2 Hz to 25 kHz 1 mHz to 25 kHz 0 to 100%

with generator ANLG 25 kHz only 2 Hz to 25 kHz 1 mHz to 25 kHz 0 to 100%

with generator ANLG 25 kHz only 0 to ± 10 V (± 5 V unsymmetrical), can be swept ±2%

0 to ± 10.0 V (± 5 V unsymmetrical) 18-bit resolution +2% <1% of rms value of AC signal (typ. <0.1%)

- $^{1)}$ Output voltage >200 mV, typ. values apply from 0.5 V to 5 V. Lower frequency >100 Hz, value in () for lower frequency <100 Hz. Level ratio LF:UF = 4:1.
- 2) Center frequency 5 kHz to 20 kHz, DFD d₂ -95 dB (typ.) with DC offset. Output voltage >200 mV, typ. values apply from 0.5 V to 5 V.
- DFD d₃: total inherent distortion of analyzer and generator; center frequency 5 kHz to 20 kHz. 4)
- Input voltage >200 mV, typ. values apply from 0.5 to 5 V. Total inherent distortion of analyzer and generator at full-scale measurement range.
- ⁵⁾ For all signals except squarewave and DIM, no DC offset for signal generation with Low Dist ON. With DC offset the AC voltage swing will be reduced, specified inherent distortion values apply to DC offset = 0.

Digital analyzers

Three analyzers differing in bandwidth, specifications and measurement functions are available for digital measurements.

Frequency range

2 Hz/10 Hz to 21.90 kHz

10 Hz/100 Hz to 87 kHz

Analyzer DIG 48 kHz DIG 192 kHz DIG 768 kHz

DIG 768 kHz 10 Hz/100 Hz to 350 kHz With analyzers DIG 192 kHz and DIG 768 kHz the number of samples is limited to 96000. This reduces the lower limit frequency and the maximum filter settling time. Frequency limits specified for the individual measurement functions apply to a sampling frequency of 48 kHz. Limits for other sampling frequencies are calculated according to the formula: $f_{\rm new} = f_{\rm 48\,kHz}$ x sampling rate/ 48 kHz.

Maximum values for analyzer DIG 768 kHz are specified in [].

Inputs

Serial (audio) Channels Audio bits Clock rate Format

Balanced input

Impedance Level (V_{PP})

Unbalanced input Impedance Level (V_{PP}) Optical input

Serial (universal)

Channels Word length Audio bits Data format Synchronization

Clock rate

Parallel Channel 1/MUX

Channel 2

Word length Audio bits Synchronization

Clock rate

Measurement functions

(all measurements at 24 bits, full scale)

RMS value, wideband

Measurement bandwidth Measurement accuracy AUTO FAST AUTO FIX Integration time AUTO FAST AUTO VALUE Filter

Spectrum

with option UPD-B2 1, 2 or both 8 to 24 32/44.1/48 kHz professional and consumer format to AES3 or IEC-958 as well as user-definable formats at all inputs XLR connector (female), transformer coupling 110 Ω , 10 k Ω , switchable min. 200 mV, max. 12 V into 110 Ω (24 V into 10 k Ω) BNC, grounded 75 Ω min. 100 mV, max. 5 V TOSLINK

15-contact DSUB connector (male) 1 and/or 2 separate or multiplexed 8/16/24/32 bits 8 to 28 bit MSB/LSB first pos./neg. edge of bit clock and word clock selectable, position of word clock within word userselectable, word select (MUX) low/high 100 Hz to 1 MHz (word clock)

37-contact DSUB connector (male) channel 1 or channels 1 and 2 multiplexed contained in option UPD-B3 (highspeed extension) 28 bits 8 to 28 word clock with pos./neg. edge, word select (MUX) low/high 100 Hz to 1 MHz

up to 0.5 times the clock rate ±0.1 dB ±0.01 dB ±0.001 dB 4.2 ms, at least 1 cycle 42 ms, at least 1 cycle 1 ms to 10 s weighting and user-definable filters, up to 4 filters combinable

post-FFT of filtered signal

RMS value, selective

Bandwidth (–0.1 dB)

Selectivity

Frequency setting

Measurement accuracy

Peak value Measurement

Measurement accuracy Interval Filter

Quasi-peak Measurement, accuracy Filter

S/N measurement routine

FFT analysis

Total harmonic distortion (THD) Fundamental Frequency tuning

Weighted harmonics

Measurement accuracy Inherent distortion¹⁾ Fundamental 42 Hz to 21.90 kHz 24 Hz to 42 Hz 12 Hz to 24 Hz Spectrum

THD+N and SINAD Fundamental

Frequency tuning

requeries rening

Stopband range

Bandwidth

Measurement accuracy Inherent distortion¹⁾ Bandwidth 20 Hz to 21.90 kHz Fundamental 28 Hz to 21.90 kHz 24 Hz to 28 Hz 20 Hz to 24 Hz Spectrum 1%, 3%, 1/12 octave, 1/3 octave and user-selectable fixed bandwidth, min. bandwidth 20 Hz 100 dB, bandpass or bandstop filter, 8th order filter, elliptical – automatic to input signal

- coupled to generator
- fixed through entered value
- sweep in user-selectable range
- ±0.2 dB + ripple of filters

with analyzer DIG 48 kHz only peak max, peak min, peak-to-peak, peak absolute ±0.2 dB at 1 kHz 20 ms to 10 s weighting and user-definable filters, up to 3 filters combinable

with analyzer DIG 48 kHz only to CCIR 468-4 weighting and user-definable filters, up to 3 filters combinable

available for measurement functions: - rms, wideband - peak - quasi-peak indication of S/N ratio in dB, no post-FFT

see FFT analyzer section

6 Hz to 21.90 kHz [100 Hz to 350 kHz] – automatic to input signal – coupled to generator – fixed through entered value any combination of d₂ to d₉, up to 21.90 kHz [350 kHz] ±0.1 dB

<–130 dB <–112 dB <–88 dB bar chart showing signal and distortion

20 Hz to 21.90 kHz [320 Hz to 350 kHz] - automatic to input signal - coupled to generator - fixed through entered value fundamental ±28 Hz, but max. up to 1st harmonic upper and lower frequency limit selectable, one additional weighting filter ±0.3 dB

<-126 dB <-109 dB <-96 dB post-FFT of filtered signal

1) Total inherent distortion of analyzer and generator.

Modulation distortion (MOD DIST)

Measurement method Frequency range lower frequency 30[400] Hz to 500 Hz¹⁾ upper frequency Measurement accuracy Inherent distortion²⁾ Level LF:UF 1:1 4:1 10.1

Spectrum

Difference frequency distortion (DFD)

Measurement method Frequency range Difference frequency Center frequency Measurement accuracy ¹¹-tortion²⁾ DFD d₂ DFD d₃ Spectrum

4 kHz¹⁾ to 21.25 kHz [348 kHz] ±0.2 dB <-133 dB <-123 dB <-115 dB bar chart showing signal and distortion

selective to DIN-IEC 268-3

selective to DIN-IEC 268-3 or 118

80 Hz [500 Hz] to 2 kHz¹⁾ 200 Hz to 20.90 kHz [348 kHz] ±0.2 dB <-130 dB <-130 dB bar chart showing signal and distortion

with analyzer DIG 48 kHz only

square/sine 3.15 kHz/15 kHz

any square/sine amplitude ratio (standard 4:1)

or 2.96 kHz/14 kHz,

±0.2 dB

<-125 dB

frequency tolerance ±3%

selective weighting of all 9 interference lines to DIN-IEC 268-3

Dynamic intermodulation distortion

(DIM) Measurement method

Test signal

Measurement accuracy Inherent distortion²⁾ Spectrum

Wow and flutter

Measurement method

OFF Weighting filter ON

Measurement accuracy Inherent noise

Spectrum

Time domain display (WAVEFORM) Trigger

Trigger level

Standard mode Trace length Interpolation Enhanced mode Word length Compressed mode

Frequency³⁾

Frequency range with rms value with THD with FFT, THD+N Accuracy

Input signal

with analyzer DIG 48 kHz only DIN-IEC, NAB, JIS, 2-sigma to IEC-386 highpass 0.5 Hz, bandwidth 600 Hz bandpass 4 Hz to IEC-386 ±3% <0.0003% weighted <0.0008% unweighted post-FFT of demodulated signal

bar chart showing signal and distortion

rising/falling edge -1 FS to +1 FS, interpolated between samples

max. 7424 points 1, 2, 4, 8, 16, 32 single channel max. 65530 points 2- to 1024-fold compression (envelope for AGC measurement), with analyzer DIG 48 kHz only

2 Hz to 21.90 kHz 6 Hz to 21.90 kHz 20 Hz to 20 kHz typ. ±5 ppm THD+N <-70 dB >-80 dBFS

Phase⁴⁾

Accuracy Display range

Group delay⁴⁾ Frequency range Accuracy in seconds

Polarity test

Measurement Display

±0.1°, 20 Hz to 20 kHz ±180° or 0 to 360°

20 Hz to 20 kHz $\Delta \phi / (\Delta f \times 360),$ where $\Delta \phi = \text{phase} \text{ accuracy in }^\circ$, $\Delta f = frequency step$

polarity of unsymmetrical input signal +POL, -POL

Digital generators

Three generators differing in frequency and test signals are available for digital signal generation. Generator Frequency range DIG 48 kHz 2 Hz to 21.90 kHz

DIG 192 kHz 2 Hz to 87 kHz DIG 768 kHz 2 Hz to 350 kHz Frequency limits indicated for the signals apply to a sampling rate of 48 kHz. Frequency limits for other sampling rates are calculated according to the formula: $f_{new} = f_{48 \text{ kHz}} \times \text{sampling rate}/48 \text{ kHz}.$ Max. values for generator DIG 768 kHz are specified in [].

Outputs	
Serial (audio) Channels Audio bits Clock rate	with option UPD-B2 1, 2 or both 8 to 24 internal: 32 kHz, 44.1 kHz, 48 kHz or synchronization to analyzer external: synchronization to word clock input (27 kHz to 55 kHz)
Format	professional and consumer format to AES 3 or IEC-958 as well as user-defin- able formats at all outputs
Balanced output	XLR connector (male), transformer coupling
Impedance Level (V _{PP} into 110 Ω) Accuracy Unbalanced output Impedance Level (V _{PP} into 75 Ω) Accuracy	$ \begin{array}{l} \text{Coupling} \\ 110 \ \Omega, \ \text{short-circuit-proof} \\ 20 \ \text{mV} \ \text{to} \ 5.1 \ \text{V}, \ \text{in steps of} \ 20 \ \text{mV} \\ \pm 1 \ \text{dB} \ (\text{rms}) \\ \text{BNC connector (female), transformer} \\ \text{coupling} \\ 75 \ \Omega, \ \text{short-circuit-proof} \\ 10 \ \text{mV} \ \text{to} \ 1.5 \ \text{V}, \ \text{in steps of} \ 10 \ \text{mV} \\ \pm 1 \ \text{dB} \ (\text{rms}) \\ \end{array} $
Optical output	TOSLINK
Serial (universal) Channels Word length Audio bits Data format Synchronization	15-contact DSUB connector (female) 1 and/or 2 separate or multiplexed 8/16/24/32 bits 8 to 28 MSB/LSB first pos./neg. edge of bit clock and word clock selectable, position of word clock within word user- selectable, word select (MUX) low/high internal: 32 kHz, 44.1 kHz, 48 kHz and multiples thereof up to max. 768 kHz external: 100 Hz to 768 kHz
Parallel Channel 1/MUX Word length Synchronization Clock rate	37-contact DSUB connector (female) channel 1 or channels 1 and 2 multiplexed 28 bits word clock with pos./neg. edge, word select (MUX) low/high internal: 32 kHz, 44.1 kHz, 48 kHz and multiples thereof up to max. 768 kHz

1) Fixed frequency independent of sampling rate.

2) Total inherent distortion of analyzer and generator.

3) Only with measurement functions RMS, THD, THD+N and FFT analysis. Only with FFT analysis at serial audio inputs (AES/EBU, S/P DIF or optical).

external: 100 Hz to 768 kHz

Signals

(All signals with 24 bits, full scale)

General characteristics

Level resolution Audio bits

Dither¹⁾ Distribution Level Frequeny accuracy

Frequency offset¹⁾ DC offset

Sine

Frequency range Total harmonic distortion (THD) Sweep parameters

MOD DIST

Frequency range lower frequency upper frequency Level ratio (LF:UF) Inherent distortion Level LF:UF 1:1 4:1

10:1 Sweep parameters

DFD

Frequency range Difference frequency Center frequency Inherent distortion³¹ DFD d₂ DFD d₃ Sweep parameters

DIM

Waveform

Inherent distortion³⁾ Sweep parameters

Multi-sine Characteristics

Frequency range

Frequency spacing

Dynamic range

Squarewave Frequency

3)

Sweep parameters

2⁻²⁴ 8 to 28 (8 to 24 at AES), LSB rounded off

Gaussian, triangular, rectangular 2⁻²⁴ FS to 1 FS ±50 ppm (internal clock), ±1 ppm ref. to clock rate 0 or +1000 ppm 0 to ±1 FS adjustable

2 Hz²⁾ to 21.90 kHz [350 kHz] <–133 dB frequency, level

for measuring the modulation distortion 30[50] Hz to 500 Hz²⁾ 4 kHz^{2]} to 21.90 kHz [350 kHz] selectable from 10:1 to 1:1

<-133 dB <-123 dB <-115 dB upper frequency, level

for measuring the difference tone

80 Hz [100 Hz] to 1 kHz²⁾ 200 Hz²⁾ to 20.90 kHz [350 kHz]

<-130 dB <-130 dB center frequency, level

for DIM measurement to DIN-IEC 268-3 (dynamic modulation distortion) square/sine 3.15 kHz/15 kHz or 2.96 kHz/14 kHz, square/sine amplitude ratio 4:1 <-125 dB level

1 to 17 spectral lines
level, frequency and phase selectable for each line
crest factor optimized to minimum or selectable

2.93 Hz to 21.90 kHz [46.88 Hz to 350 kHz] adjustable from 2.93 Hz [46.88 Hz] with <0.01% resolution or matching to FFT frequency spacing >133 dBFS

2 Hz²⁾ to 12 kHz [50 Hz to 192 kHz], 2-sample resolution frequency, level

Sine burst, sine² burst

Burst time⁴⁾ Interval⁴⁾ Low level

Sweep parameters

Noise

Noise in time domain Distribution Noise in frequency domain Frequency range

Frequency spacing

Distribution Crest factor

Arbitrary waveform Memory depth Clock rate

Polarity test signal

Sine² burst with following characteristics: Frequency On-time Interval

FM signal Carrier frequency

Modulation frequency Modulation

AM signal Carrier frequency Modulation frequency Modulation

DC voltage Level range

Digital audio protocol (with option UPD-B2)

Generator

Validity bit Error simulation

Channel status data

Local time code CRC User data

Analyzer Display

Error indication

Error counter Clock-rate measurement 1 sample up to 60 s burst time up to 60 s 0 to burst level, absolute or relative to burst level (0 with sine² burst) burst frequency, level, time, interval

not with generator DIG 768 kHz Gaussian, triangular, rectangular

2.93 Hz to 21.90 kHz [46.88 Hz to 350 kHz] adjustable from 2.93 Hz [46.88 Hz] with <0.01% resolution or matching to FTF frequency spacing white, pink, 1/3 octave, defined by file optimized to minimum or selectable

loaded from file max. 16384 sample rate of generator

with generator DIG 48 kHz only

1.2 kHz²⁾ 1 cycle 2 cycles

with generator DIG 48 kHz only 2 Hz^{21} to 21.90 kHz 1 mHz^{21} to 21.90 kHz 0 to 100%

with generator DIG 48 kHz only 2 Hz²¹ to 21.9 kHz 1 mHz²¹ to 21.9 kHz 0 to 100%

with generator DIG 48 kHz only 0 to ± 1 FS, can be swept

NONE, L, R, L+R parity/block error/sequence error/ CRC error, correctly or with adjustable error rate mnemonic entry with user-definable masks, predefined masks for professional and consumer format to AES3 or IEC-958

automatic generation selectable automatic generation selectable loaded from file (max. 16384 byte) or set to zero

validity bit L and R
change of status bits
differences between L and R
block errors, sequence errors, clock-rate errors, preamble errors
parity, CRC
50 ppm

 With signals sine, DFD and MOD DIST. Dither not with generator DIG 768 kHz.
 Fixed frequency independent of sampling rate.

Total inherent distortion of analyzer and generator.

¹ 1-sample resolution, duration max. 20 ms with generator DIG 768 kHz.

user-definable mnemonic display of data fields, predefined settings for professional and consumer format to AES3 or IEC-958. binary and hexadecimal format user-definable mnemonic display, block-synchronized

User bit display

Jitter and interface tester (option UPD-B22)

For non-specified characteristics the data of UPD-B2 apply

Generator

Level (V_{pp} into 110 Ω)

Clock rate Internal

External

Jitter injection Waveform Frequency range Amplitude (peak-to-peak) Common mode signal Waveform Frequency range Amplitude (V_{pp}) Phase (output to reference)

Cable simulator Long cable Short cable

Analyzer Impedance Amplitude (V_{pp})

Sampling rate

Jitter measurement

Reclocking

Common mode test Amplitude (V_{pp}) Frequency Spectrum Phase (input to reference)

Sync output

FFT analyzer

2 Hz to 350 kHz Frequency range, digital 2 Hz to 300 kHz analog Dynamic range Digital >135 dB 120 dB/105 dB¹ Analyzer ANLG 22 kHz Analyzer ANLG 100/300 kHz 115 dB/85 dB¹⁾ Noise floor Digital -160 dB -140 dB/110 dB¹⁾ Analyzer ANLG 22 kHz Analyzer ANLG 100/300 kHz -120 dB/90 dB¹⁾

0 to 2 V, unbalanced continuously adjustable between 30 kHz and 52.5 kHz and

0 to 8 V, in 240 steps, balanced,

synchronization to analyzer 30 kHz to 52.5 kHz, synchronization to word clock input, video sync, DARS, 1024 kHz

sine, noise 10 Hz to 110 kHz 0 to 10 UI for balanced output sine 20 Hz to 110 kHz 0 to 20 V adjustable between -64 and +64 UI (corresp. to ±50% of frame)

100 m typical audio cable typ. 30 ns rise time

110 Ω (bal.), 75 Ω (unbal.) 200 mV to 12 V (balanced) 100 mV to 5 V (unbalanced) 30 kHz to 52.5 kHz (phase, jitter and common-mode measurement) amplitude, frequency, spectrum 0 to 5 UI typ. for f<500 Hz, decreasing to 0.5 UI for up to 50 kHz (at 48 kHz) input signal available at reference output (rear of instrument) after removal of iitter at balanced input 0 to 30 V 20 Hz to 110 kHz 20 Hz to 110 kHz -64 to +64 UI (corresp. to ±50% of frame) switchable to generator, REF generator, audio input, REF input or reference PLL; word clock or biphase clock selectable FFT size 256, 512, 1 k, 2 k, 4 k, 8 k points (16 k with zoom factor 2) Window functions rectangular, Hann, Blackman-Harris, Rife-Vincent 1 to 3, Hamming, flat top, Kaiser ($\beta = 1$ to 20) Resolution from 0.023 Hz with zoom, from 5.86 Hz without zoom – 2 to 256 with ANLG 22 kHz and Zoom DIG 48 kHz - 2 to 16 with ANLG 100/300 kHz - 2 to 8 with DIG 192/768 kHz 1 to 256, exponential and normal Averaging

Filter

For all analog and digital analyzers. Up to 4 filters can be combined as required. All filters are digital filters with a coefficient accuracy of 32 bit floating point (exception: analog notch filter).

Weighting filter

- A weighting - C message
- CCITT
- CCIR weighted, unweighted
- CCIR ARM
- deemphasis 50/15, 50, 75, J.17
- rumble weighted, unweighted
- DC noise highpass
- IEC tuner
- jitter weighted

User-definable filters

Design parameters: 8th order elliptical, type C (for highpass and lowpass filters also 4th order selectable), passband ripple +0/-0.1 dB, stopband attenuation approx. 20 dB to 120 dB selectable in steps of approx. 10 dB (highpass and low-pass filters: stopband attenuation 40 dB to 120 dB).

Highpass, lowpass filters	limit frequencies (–0.1 dB) selectable, stopband indicated
Bandpass, bandstop filters	passband (–0.1 dB) selectable, stopband indicated
Notch filter	center frequency and width (–0.1 dB) selectable, stopband indicated
Third octave and octave filters	center frequency selectable, bandwidth (–0.1 dB) indicated
File-defined filters	any 8th order filter cascaded from 4 biquads, defined in the z plane by poles/zeroes or coefficients

Analog notch filter

For measurements on signals with high S/N ratio, this filter improves the dynamic range of the analyzer by up to 30 dB to 140 dB for analyzer 22 kHz, or 120 dB for analyzer 110 kHz/300 kHz (typical noise floor for FFT). The filter is also used for measuring THD, THD+N and MOD DIST with dynamic mode precision.

Characteristics available in analog analyzers with measurement functions: - rms, wideband - rms, selective – quasi-peak – FFT analysis 10 Hz to 100 kHz center frequency (f_c) Frequency range - automatic to input signal Frequency tuning - coupled to generato - fixed through entered value Stopband typ.>30 dB, f_c ±0.5% typ. –3 dB at 0.77 x f_c and 1.3 x f_c , typ. ± 0.5 dB outside 0.5 x f_c to 2 x f_c Passband

1) With / without analog notch filter.

Audio monitor/parallel I/O interface (option UPD-B5)

6.3 mm jack

10 Ω, short-circuit-proof

25-contact DSUB, female

for driving signal routing switchers

max. 8 V max. 50 mA

600 Ω

Headphones connector

Output voltage (V_P) Output current (I_P) Source impedance Recommended headphones impedance

Parallel I/O interface Connector

Sweep

Generator sweep		
Parameters	frequency, level, with bursts also interval and duration, one- or two-dimensional	
Sweep	linear, logarithmic, tabular, single, continuous, manual	
Stepping	 automatic after end of measurement time delay, fixed or loaded table 	
Analyzer sweep		
Parameters	frequency or level of input signal	
Sweep Trigger	single, continuous – delayed (0 to 10 s) after input level or input frequency variation, settling function selectable – time-controlled	
Settling	for level, frequency, phase, distortion measurements, settling function: exponential, flat or av- eraging	
Sweep speed RMS measurement 20 Hz to 20 kHz, 30-point generator sweep, logarithmic (frequency measurement switched off, Low Dist off).		

1 s

2.5 s

Display of results

with

AUTO FAST

AUTO

Units Level (analog)	V, dBu, dBV, W, dBm, difference (Δ), deviation (Δ%) and ratio (without dimension, %, dBr) to reference value
Level (digital)	FS, %FS, dBFS, LSBs deviation (Δ%) or ratio (dBr) to refer- ence value
Distortion	% or dB, referred to signal amplitude, THD and THD+N in all variable level units (absolute or relative to selectable reference value)
Frequency	Hz, difference (Δ), deviation (Δ%) and ratio (as quotient f/f _{ref} , 1/3 octave, octave or decade) to reference value (entered or stored, current generator frequency)
Phase	°, rad, difference (Δ) to reference value (entered or stored)

Reference value (level):

Fixed value (entered or stored). Current value of a channel or generator signal: permits direct measurement of gain, linearity, channel difference, crosstalk. In sweep mode, traces (other trace or loaded from file) can be used as a reference too.

Graphical display of results Monitor Display modes Display functions	 8.4" LCD, colour display of any sweep trace display of trace groups bargraph display with min./max.values spectrum, also as waterfall display list of results bar charts for THD and intermodulation measurements autoscale X-axis zoom full-screen and part-screen mode 2 vertical, 1 horizontal cursor line search function for max. values marker for harmonics (spectrum) user-labelling for graphs change of unit and scale also possible for loaded traces
Test reports Functions Printer driver Plotter language Interfaces	 screen copy to printer, plotter or file (PCX, HPGL, Postscript) lists of results sweep lists tolerance curves list of out-of-tolerance values equalizer curves supplied for approx. 130 printers HP-GL 2 x RS-232, Centronics,
Storage function	IEC 625 (option UPD-B4) – instrument settings – spectra – sweep results – sweep lists – tolerance curves – equalizer traces
Remote control	via IEC 625-2 (IEEE 488), commands largely to SCPI (option UPD-B4)

General data

Operating temperature range Storage temperature range Humidity EMI EMS Power supply

Dimensions ($W \times H \times D$) Weight

0 to +45°C –20°C to +60°C max. 85% for max. 60 days, below 65% on average/year, no condensation EN 50081-1 EN 50082-1 100/120/220/230 V±10%, 47 Hz to 63 Hz, 290 VA $435~\text{mm} \ge 236~\text{mm} \ge 475~\text{mm}$ 22 kg

Ordering information

Order designation	Audio Analyzer UPD	1030.7500.05
Accessories supplied	power cable, operating manual, backup system disks with MS-DOS operating system and user manual, backup program disk with operating and measurement software	
Options		
Low Distortion Generator	UPD-B1	1078.2601.02
AES/EBU Interface	UPD-B2	1031.2301.02
Jitter and Interface Tester	UPD-B22	1078.6503.02
High-Speed Extension	UPD-B3	1031.2001.02
IEC-625/IEEE-488 Bus Interface	UPD-B4	1031.2901.02
Audio Monitor	UPD-B5	1031.5300.02
Universal Sequence Controller	UPD-K1	1031.4204.02
Arbitrary Waveform Designer	UPD-K2	1031.4404.02
Automatic Line Measurement		
to ITU-T O.33	UPD-K33	1031.5500.02
Recommended extras		
19″ Adapter	ZZA-95	0396.4911.00
Service manual		1030.7551.24
Service Kit	UPD-Z2	1031.3208.02



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